

Workshop on Software-Embedded Systems Testing (WSEST)



NIST Gaithersburg, MD, Nov 8,9, 1999

The workshop will focus on the problems of testing mixed-signal systems with embedded-software. The systems considered include individual IC devices to complete instruments. The scope will include, but is not limited to problems associated with:

Adaptive Systems
Automatic Test Generation
Black Box and Glass Box Views
Built-in-Test Support
Controlling Test Complexity Growth
Detecting Design Defects
Detecting Manufacturing Defects
Fault Tolerance Verification

Maintaining Accurate Models
Modular Redundancy
Reconfigurable Devices
Software Constraints for Testability
Software Validation
System Reliability
Test-Space Searching Techniques

Prospective authors should submit an extended abstract (in English only) 1 to 2 pages in length. The submission should include author name(s), affiliation(s), address(es), phone number(s), fax number(s), email address(es), and the contact author. Abstracts should be submitted no later than August 1, 1999, to:

Jerry Stenbakken, WSEST Chairman
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- **August 1, 1999** - Abstract submission deadline.
- **September 15, 1999** - Author notification of acceptance or rejection.
- **October 15, 1999** - Final manuscript due date.

Papers will be reviewed by the Technical Program Committee. Authors will be notified about acceptance or rejection by September 15, 1999, and the final manuscripts are due by October 15, 1999. Submission of abstracts implies authors' willingness to register at the workshop and present the paper(s). An informal proceedings will be available at the end of the workshop, and final papers will be posted on the workshop web page.

For further information, contact Jerry Stenbakken Workshop Chairman, or visit the WSEST web site at: <http://www.eeel.nist.gov/wsest>